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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/812,409	03/29/2004	David Alan Baldwin	53757-5013	1261
MORGAN, LEWIS & BOCKIUS LLP 1701 Market Street			EXAMINER	
			MCDONALD, RODNEY GLENN	
Philadelphia, PA 19103-2921		·	ART UNIT	PAPER NUMBER
			1753	
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			MAIL DATE	DELIVERY MODE
			07/23/2007	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)			
	10/812,409	BALDWIN ET AL.			
Office Action Summary	Examiner	Art Unit			
	Rodney G. McDonald	1753			
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the	correspondence address			
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailin earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATIO 136(a). In no event, however, may a reply be to will apply and will expire SIX (6) MONTHS from e, cause the application to become ABANDON	N. imely filed in the mailing date of this communication. ED (35 U.S.C. § 133).			
Status					
Responsive to communication(s) filed on 2a) ☐ This action is FINAL . 2b) ☐ This 3) ☐ Since this application is in condition for alloware closed in accordance with the practice under the practice.	s action is non-final. ince except for formal matters, pr				
Disposition of Claims					
4) ☐ Claim(s) 1-5 is/are pending in the application. 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-5 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or					
Application Papers					
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Example 2.	cepted or b) objected to by the drawing(s) be held in abeyance. So tion is required if the drawing(s) is o	ee 37 CFR 1.85(a). bjected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summar Paper No(s)/Mail [5) Notice of Informal 6) Other:	Date			

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DETAILED ACTION

Double Patenting

The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. A nonstatutory obviousness-type double patenting rejection is appropriate where the conflicting claims are not identical, but at least one examined application claim is not patentably distinct from the reference claim(s) because the examined application claim is either anticipated by, or would have been obvious over, the reference claim(s). See, e.g., *In re Berg*, 140 F.3d 1428, 46 USPQ2d 1226 (Fed. Cir. 1998); *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) or 1.321(d) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent either is shown to be commonly owned with this application, or claims an invention made as a result of activities undertaken within the scope of a joint research agreement.

Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

Claims 1-4 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-4 of U.S. Patent No. 6,402,904 in view of Quazi (U.S. Pat. 4,693,805).

Claims 1-4 of U.S. Pat. No. 6,402,904 teach the claimed subject matter except that the claims are sputtering a target instead of etching a substrate.

The Examiner views that target as a material being sputter etched. Quazi shows that an electrode subjected to sputtering can be either a target for sputter deposition or a substrate for sputter etching. (See Abstract; Claims 5, 8, 10, 11)

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to have modified U.S. Pat. 6,402,904 by replacing the target with a substrate to be sputter etched as taught by Quazi because Qauzi show that such replacement will sputter etch a substrate.

Claims 1-4 are rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-25 of U.S. Patent No. 6,679,976 in view of Quazi (U.S. Pat. 4,693,805).

Claims 1-25 of U.S. Pat. No. 6,679,976 teach the claimed subject matter except that the claims are sputtering targets instead of etching a substrate.

The Examiner views the targets as a material being sputter etched. Quazi shows that an electrode subjected to sputtering can be either a target for sputter deposition or a substrate for sputter etching. (See Abstract; Claims 5, 8, 10, 11)

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to have modified U.S. Pat. 6,402,904 by replacing the targets with a substrate to be sputter etched as taught by Quazi because Qauzi show that such replacement will sputter etch a substrate.

Claim 5 is rejected on the ground of nonstatutory obviousness-type double patenting as being unpatentable over claims 1-4 of U.S. Patent No. 6,402,904 or Claims 1-25 of U.S. Pat. 6,679,976 in view of Quazi (U.S. Pat. 4,693,805) and further in view of Petrmichl et al. (U.S. Pat. 5,679,413) and Boyd et al. (U.S. Pat. 4,309,267).

The differences not yet discussed are the electron voltage used for etching and the angle of the substrate.

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Petrmichl et al. teach utilizing during sputtering etching energies for the ions above 20 eV and preferably less than 500 eV. (Column 10 lines 27-41)

The motivation for utilizing the feature of Petrmichl et al. is that it allows for reducing the amount of atomic scale damage. (Column 10 lines 40-41)

Boyd et al. teach supporting the substrate at an angle during sputter etching. (See abstract)

The motivation for utilizing the feature of Boyd et al. is that it allows for directionally etching the substrate. (Column 3 line 50)

Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention wad made to have utilized the features of Petrmichl et al. and Boyd et al. because it allows for reducing atomic scale damage and directionally etching the substrate.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Rodney G. McDonald whose telephone number is 571-272-1340. The examiner can normally be reached on M-TH with every Friday off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nam X. Nguyen can be reached on 571-272-1342. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Rodney G. McDonald Primary Examiner

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RM July 18, 2007